

BS ISO 14706:2014



BSI Standards Publication

**Surface chemical analysis
— Determination of surface
elemental contamination
on silicon wafers by total-
reflection X-ray fluorescence
(TXRF) spectroscopy**

National foreword

This British Standard is the UK implementation of ISO 14706:2014. It supersedes BS ISO 14706:2000 which is withdrawn.

The UK participation in its preparation was entrusted to Technical Committee CII/60, Surface chemical analysis.

A list of organizations represented on this committee can be obtained on request to its secretary.

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Amendments issued since publication

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